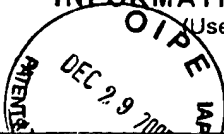


<b>FORM HDP-1449 (Based on Form PTO-1449)</b>  <b>PATENT AND TRADEMARK OFFICE</b> <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)  	ATTORNEY DOCKET NO.		SERIAL NO.
	9319S-000617		10/760,176
	APPLICANT		
	Reiko Wachi		
	FILING DATE	GROUP	
January 16, 2004	2811		

Sheet 1 of 1

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

FOREIGN PATENT DOCUMENTS							
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes No	
1.	SL	08-327814	12/13/1996	Japan		X	
2.	SL	09-068721 **	3/11/1997	Japan		X	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
1.	SL	Communication from Korean Patent Office re: related application.

\*One or more of the English translation documents submitted herewith may be Abstracts only or partial machine created translations from the Japanese Patent Office. As such, the submitter does not necessarily vouch for their accuracy. Additional information may be obtained from the Japanese Patent Office web site at [www.jpo.go.jp](http://www.jpo.go.jp)

\*\* Previously cited to PTO

Examiner:	/Steven Loke/	Date Considered:	06/22/2006
-----------	---------------	------------------	------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449)  <b>PATENT AND TRADEMARK OFFICE</b> <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)  Sheet 1 of 1	ATTORNEY DOCKET NO.	SERIAL NO.
	9319S-000617	10/760,176
	APPLICANT	
	Reiko WACHI	
	FILING DATE	GROUP
	January 16, 2004	2811

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	SL	2002-0063834	03-12-1841	Rider		

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes No
1.	SL	2002-268200	09-18-2002	Japan		X
2.	SL	08-321025	12-03-1996	Japan		X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
1.	SL	Examination result issued in corresponding Chinese application.

\*One or more of the English translation documents submitted herewith may be Abstracts only or partial machine created translations from the Japanese Patent Office. As such, the submitter does not necessarily vouch for their accuracy. Additional information may be obtained from the Japanese Patent Office web site at [www.jpo.go.jp](http://www.jpo.go.jp)

Examiner:	/Steven Loke/	Date Considered:	06/22/2006
-----------	---------------	------------------	------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.